



IFW

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): YAMAMOTO	Atty. Dkt.: 01-545
Serial No.: 10/764,541	Group Art Unit: 2859
Filed: January 27, 2004	Examiner: Unknown
Title: OVERTEMPERATURE DETECTION DEVICE AND SEMICONDUCTOR INTEGRATED CIRCUIT DEVICE	

Commissioner for Patents
Arlington, VA 22202

Date: July 6, 2004

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Sir:

Pursuant to 37 C.F.R. §1.56, the reference listed on the attached Form PTO-1449 is being brought to the attention of the Examiner without any admission that it constitutes statutory prior art, or without any admission that it contains subject matter that anticipates the invention or renders the invention obvious to a person of ordinary skill in the art.

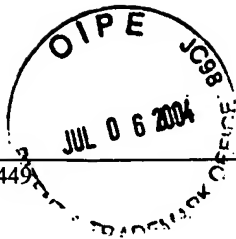
The Examiner should note that, due to a typographical error, the listed reference was incorrectly identified as JP-A-2001-244141 in an information disclosure statement filed concurrently with the present application.

The Examiner is requested to initial the attached PTO Form-1449 and to return a copy of same to the undersigned attorney as proof that the listed reference has been considered and made of record.

Respectfully submitted,

David G. Posz
Reg. No. 37,701

Posz & Bethards, PLC
11250 Roger Bacon Drive, Suite 10
Reston, VA 20190
(703) 707-9110 (phone)
Customer No. 23400



PATENT APPLICATION

Page 1 of 1

FORM PTO-1449	ATTY. DKT NO.	01-545	SER. NO.	10/764,541
	APPLICANT	YAMAMOTO		
	FILING DATE	January 27, 2004	GROUP	2859

REFERENCE DESIGNATION

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS

FOREIGN PATENT DOCUMENTS

TRANSLATION

		DOCUMENT NUMBER	DATE	COUNTRY	NAME	CLASS	SUB CLASS	YES	NO	
										Eng. Abstract
		JP-A-2001-244411 (Discussed in page 1 of the spec.)	9/7/01	JAPAN						X

* Full English text of the JP Document will be available in machine-translated form from JP (Japanese Patent Office) English language web site at <http://www1.ipdl.jpo.go.jp/PA1/cgi-bin/PA1INDEX>.

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

EXAMINER		DATE CONSIDERED